

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 6,989,540 B2
APPLICATION NO. : 10/705860
DATED : January 24, 2006
INVENTOR(S) : Morii et al.

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

COLUMN 1:

Line 48, "detect" should read -- defect --.

COLUMN 3:

Line 25, "from" should be deleted.

COLUMN 9:

Line 6, "ohmic" should read -- first ohmic --.

COLUMN 12:

Line 20, "wiring. 201," should read -- wiring 201, --.

COLUMN 13:

Line 19, "layer" should read -- layer structure --.

COLUMN 15:

Line 3, "complicated therefore," should read -- complicated. Therefore, --.

COLUMN 16:

Line 55, "TFT, After" should read -- TFT. After --.

COLUMN 17:

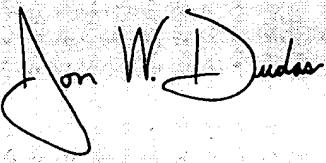
Line 44, "another," should read -- other, --.

COLUMN 19:

Line 63, "X-ray On" should read -- X-ray. On --.

Signed and Sealed this

Twelfth Day of December, 2006



JON W. DUDAS
Director of the United States Patent and Trademark Office